

EMC Zurich 2007 - 18th International Zurich Symposium on Electromagnetic Compatibility

**Munich, Germany
24-28 September 2007**

IEEE Catalog Number: CFP07628-PRT
ISBN 10: 3-9523286-1-8
ISBN 13: 978-3-9523286-1-3

TABLE OF CONTENTS

Chip and Package Level EMC

Modeling of Dynamic Switching Currents of Digital VLSI IC Modules and Verification by On-Chip Measurement	1
<i>Andreas Gstöttner¹, Jacek Kruppa², Mario Huemer³; ¹University of Erlangen-Nuremberg, Germany ; ²Infineon Technologies AG, Germany; ³Klagenfurt University, Austria</i>	
Behavioral Macromodels of Digital Integrated Circuits for RF Immunity Prediction	5
<i>I.S. Stievano, E. Vialardi, F.G. Canavero, Politecnico di Torino, Italy</i>	
On-Chip EMC Issue: The Implementation of Patterned Ground Shields for Silicon Devices	9
<i>Wen-Yan Yin, Shanghai Jiao Tong University, China</i>	
Using Neural Networks for Predicting the Integrated Circuits Susceptibility to Conducted Electromagnetic Disturbances	13
<i>Imad Chahine, Moncef Kadi, Eric Gaboriaud, Anne Louis, Belahcene Mazari, IRSEEM, France</i>	

Advances in EMC Modeling

Rigorous Characterization of EMC Antennas	17
<i>Dirk Baumann¹, Christophe Fumeaux², Rüdiger Vahldieck², Er-Ping Li¹; ¹IHP, Singapore ; ²ETH Zürich, Switzerland</i>	
Investigation of Near Field Data Sampling Approaches for Far Field Radiation Prediction of PCBs by Genetic Algorithm	21
<i>Hongmei Fan, Franz Schlagenhaufer, WATRI, Australia</i>	
An Automatic Multi-Level Solver Switching Strategy for PEEC-Based EMC Simulation	25
<i>Tanja Clees¹, Tatiana Samrowski¹, Martin Ludwig Zitzmann², Robert Weigel³; ¹Fraunhofer SCAI, Germany ; ²BMW Group, Germany; ³University of Erlangen-Nuremberg, Germany</i>	
Improvement of Accuracy Using Majority Decision for Far Field Estimation by Source Modelling Method	29
<i>N. Matsuo¹, Nobuo Kuwabara¹, Y. Okubo¹, M. Kawabata²; ¹Kyushu Institute of Technology, Japan ; ²Fukuoka Industrial Technology Center, Japan</i>	

Human Exposure Modeling

EMC Modelling of Cardiac Pacemakers	33
<i>Stefan Schenke, Lars Ole Fichte, Stefan Dickmann, Helmut-Schmidt-Universität, Germany</i>	
Computed SAR Distributions for the Occupants of a Car with a 400 MHz Transmitter on the Rear Seat	37
<i>Alastair R. Ruddle, MIRA Limited, UK</i>	
Dispersive Effect of UWB Pulse on Human Head	41
<i>Taehong Kim, Jeonglan Kim, Jeongki Pack, Chungnam National University, Korea</i>	
SAR Estimations of Pregnant Woman During MR Imaging for Abdomen by Numerical Calculations	45
<i>Kazuyuki Saito¹, Satoru Kikuchi¹, Masaharu Takahashi¹, Koichi Ito¹, Hiroo Ikehira²; ¹Chiba University, Japan ; ²National Institute of Radiological Sciences, Japan</i>	

EMC at PCB (power, transients and lines)

Prediction of EMI Behaviour in Terms of Passive Component Placement	49
<i>E. Hoene, A. Lissner, S. Guttowski, Fraunhofer IZM, Germany</i>	
Modelling of Transient Waveforms for Printed Circuit Board Circuits in Power Electronics	53
<i>Gordana Felic¹, Andrea Dolente²; ¹National ICT Australia, Australia ; ²University of Bologna, Italy</i>	
Noise Propagation for Induced Fast Transient Impulses on PCB-Level	57
<i>M. Taki¹, W. John², C. Hedayat¹, U. Hilleringmann¹; ¹University of Paderborn, Germany ; ²Fraunhofer IZM, Germany</i>	
Generation of Passive Macromodels for Lossy Multiconductor Transmission Lines	61
<i>Alessandro Chinea, Stefano Grivet-Talocia, Politecnico di Torino, Italy</i>	

A Lossy Interconnect Modeling in Both the Time and the Frequency Domain Using a Synthesis Method of Lossy Nonuniform Transmission Line	65
<i>Toshikazu Sekine¹, Daiki Ichikawa¹, Yasuhiro Takahashi¹, Kunikatsu Kobayashi²; ¹Gifu University, Japan ; ²Yamagata University, Japan</i>	

EMC of ICs

Unexpected Failure in Power-Rail ESD Clamp Circuits of CMOS Integrated Circuits in Microelectronics Systems During Electrical Fast Transient (EFT) Test and the Re-Design Solution	69
<i>Ming-Dou Ker, Cheng-Cheng Yen, National Chiao-Tung University, Taiwan</i>	
EMC Test Specification for Integrated Circuits	73
<i>Frank Klotz, Infineon Technologies AG, Germany</i>	
Predicting the Immunity of Integrated Circuits Through Measurement Methods and Simulation Models	79
<i>Ali Alaeldine¹, Jérôme Cordi², Richard Perdriau¹, Mohamed Ramdani¹, Jean-Luc Levant²; ¹ESEO, France ; ²Atmel Nantes, France</i>	
Application and Limits of IC and PCB Scanning Methods for Immunity Analysis	83
<i>David Pommerenke, Giorgi Muchaidze, Jayong Koo, Qing Cai, Jin Min, University of Missouri-Rolla, USA</i>	

Modeling of Shielding and Enclosures

Fast and Accurate Evaluation of Enclosures with the Method of Moments by Using Splay Trees	87
<i>Femke Olyslager, Jan Fostier, Joris Peeters, Daniël De Zutter, Ghent University, Belgium</i>	
EMC Simulation of Complex PCB Inside a Metallic Enclosure and Shielding Effectiveness Analysis	91
<i>Antonio Ciccomancini Scogna, Martin Schauer, CST of America Inc., USA</i>	
FDTD Analysis of the Field Penetration Through Lossy Materials in a Reverberation Chamber	95
<i>Gabriele Gradoni, Franco Moglie, Anna Pia Pastore, Valter Mariani Primiani, Università Politecnica delle Marche, Italy</i>	
Emission in Reverberation Chamber: Numerical Evaluation of the Total Power Radiated by a Wire with a Stochastic Collocation Method	99
<i>F. Diouf¹, Françoise Paladian¹, M. Fogli², C. Chauvière³, Pierre Bonnet¹; ¹LASMEA, France ; ²LaMI, France; ³LM - UMR 6620, France</i>	

EMC at PCB (modeling, optimization and radiation)

GA-Optimization for Finding Decoupling Capacitors to Damp the Rectangular Power-Bus Resonances	103
<i>Sungtek Kahng, University of Incheon, Korea</i>	
Prediction of Electromagnetic Emissions from PCBs with Interconnections Through Common-Mode Antenna Model	107
<i>Yoshitaka Toyota¹, Akifumi Sadatoshi¹, Tetsushi Watanabe², Kengo Iokibe¹, Ryuji Koga¹, Osami Wada³; ¹Okayama University, Japan ; ²ITCO, Japan; ³Kyoto University, Japan</i>	
Single-Piece State-Space Behavioral Models for IC Output Buffers	111
<i>C. Siviero, I.S. Stievano, P. Savi, I.A. Maio, F.G. Canavero, Politecnico di Torino, Italy</i>	
Mixed Time/Frequency-Domain Modeling of Cross-Talk Phenomena in Coupled Microstrip Lines Terminated with Digital Circuit	115
<i>Andrzej S. Ciminski¹, Bogdan J. Janiczak²; ¹Independent Researcher, Sweden ; ²Gdansk University of Technology, Poland</i>	

Modeling of EMC Interactions

A Modular Junction Topological Approach to System Interaction Problems: Simulation and Validation	119
<i>Phumin Kirawanich, James E. Thompson, Naz E. Islam, University of Missouri, USA</i>	
Modelling Interactions Between Multiport-Systems and Canonical Stochastic Environments	123
<i>B.L. Michelsen, ONERA, France</i>	
A Physical Decomposition of Three-Phase Variables into Common and Differential Mode Quantities	127
<i>Francesco Della Torre, Sonia Leva, Adriano Paolo Morando, Politecnico di Milano, Italy</i>	
Comments on “A Comparative Study of Vector Fitting and Orthonormal Vector Fitting Techniques for EMC Applications”	131
<i>Bjørn Gustavsen, SINTEF Energy Research, Norway</i>	

Techniques for Exposure Measurements

Reproducibility of GSM and UMTS EMF Measurements	135
<i>P. Fritschi, B. Eicher, H. Lehmann, Swisscom Ltd., Switzerland</i>	
Influence of Source-Phantom Multiple Interactions on the Field Transmitted in a Flat Phantom ...	139
<i>Benoît Derat¹, Andrea Cozza², Jean-Charles Bolomey²; ¹Sagem Communication, France ; ²Supélec, France</i>	
A Gain Calibration in the Liquid Including the Effects of Fresnel Field and Systematic Uncertainty	143
<i>Nozomu Ishii¹, Hiroki Shiga¹, Ken-ichi Sato², Lira Hamada³, Soichi Watanabe³; ¹Niigata University, Japan ; ²NTT Advanced Technology, Japan; ³NICT, Japan</i>	
The Comparison Measurement for SAR by Thermal Evaluation and the Electric Field Probe	147
<i>Yoshinobu Okano, Musashi Institute of Technology, Japan</i>	
Development of a Liquid-Type Human-Body Equivalent Antenna Using NaCl Solution	151
<i>Yoshihide Takahashi¹, Takuji Arima¹, Pornanong Pongpaibool², Soichi Watanabe², Toru Uno¹; ¹Tokyo University of Agriculture & Technology, Japan ; ²NICT, Japan</i>	

Automotive 1

A Method to Convert Scattering Parameters from Common Mode to Differential Mode for Automotive Applications	155
<i>Ye Zhu¹, Marco Klingler¹, Françoise Paladian²; ¹PSA Peugeot Citroën, France ; ²LASMEA, France</i>	
Worst Case Signal Integrity Analysis for In-Vehicle Data Transmission via UTP Cables	159
<i>Volker Zwillich¹, Wolfgang Menzel¹, Helmut Leier²; ¹University of Ulm, Germany ; ²DaimlerChrysler AG, Germany</i>	
Experimental Validations of the “Equivalent Cable Bundle Method”	163
<i>G. Andrieu¹, L. Koné², F. Bocquet³, B. Démoulin², Jean-Philippe Parmantier⁴; ¹XLIM, France ; ²IEMN, France; ³Renault Technocentre, France; ⁴ONERA, France</i>	
Estimation of Electromagnetic Coupling Phenomena in a Vehicle Wiring Harness Using Characteristic Transfer Functions	167
<i>Michael Zerrer¹, Martin Aidam², Wolfgang Koehler¹, Stefan Tenbohlen¹, Kurt Feser¹; ¹University of Stuttgart, Germany ; ²DaimlerChrysler AG, Germany</i>	

Lightning and its Effects

Lightning-Induced Currents in a Buried Loop Conductor and a Grounded Vertical Conductor	171
<i>Jens Schoene, Martin A. Uman, Vladimir A. Rakov, Jason Jerauld, Joseph Howard, Britt D. Hanley, Keith J. Rambo, Brian DeCarlo, University of Florida, USA</i>	
A New Formulation for Lightning Return-Stroke Models of Engineering Type	175
<i>Grzegorz Maslowski¹, Vladimir A. Rakov²; ¹Rzeszow University of Technology, Poland ; ²University of Florida, USA</i>	
Electric Fields at the Top of Tall Building Associated with Nearby Lightning Return Strokes	179
<i>Yoshihiro Baba¹, Vladimir A. Rakov²; ¹Doshisha University, Japan ; ²University of Florida, USA</i>	

Radiation and Scattering in EMC

MoM Based EMI Analysis on Large Wind Turbine GSM 900 MHz Communication	183
Backup-System	183
<i>B. Lewke¹, Florian Krug², J. Kindersberger¹; ¹Technische Universität München, Germany ; ²GE Global Research, Germany</i>	
Analysis of the Field Radiated by a Rotating Electric Dipole Inside a Resonant Chamber	187
<i>G. Cerri, R. De Leo, Valter Mariani Primiani, C. Monteverde, P. Russo, Università Politecnica delle Marche, Italy</i>	
Safety Distances Underneath Vertically Polarized Base Station Antennas	191
<i>Michael A. Baldauf, Sandra Knörzer, Juan A. Pontes, Werner Wiesbeck, Universität Karlsruhe (TH), Germany</i>	

Automotive 2

High Voltage Automotive EMC Component Measurements Using an Artificial Network	195
<i>Jody J. Nelson¹, William Goodwin², Mark Steffka², William Ivan², Markus Kopp³; ¹DaimlerChrysler AG, Germany ; ²General Motors, USA; ³Ansoft Corporation, USA</i>	
Analytical HF Model for Multipole DC Motors	201
<i>Jens Benecke, Stefan Dickmann, Helmut-Schmidt-Universität, Germany</i>	
HEV System EMC Investigation During Transient Operations	205
<i>Jody J. Nelson, Martin Aidam, DaimlerChrysler AG, Germany</i>	
Investigation of Conducted Disturbance from Driving System in Fuel Cell Bus	209
<i>Bo Zhang, Shaofeng Yu, Wei Li, Yong Huang, Jinliang He, Tsinghua University, China</i>	

Interactive Forum

Induced Currents Due to Nearby Lightning Strike to a Mobile Radar System: An Hybrid 3D/Circuit Analysis	213
<i>G. Antonini¹, M. Cocchini¹, A. Dominicis², M. Italiani¹, A. Orlandi¹; ¹University of L'Aquila, Italy ; ²SELEX Sistemi Integrati S.p.A., Italy</i>	
Characteristics of Phase-Delay Time on Meander Differential Signal Lines and a Shielded Meander Differential Signal Line	217
<i>Shigeo Nara¹, Kohji Koshiji²; ¹Fuji Xerox Co. Ltd., Japan ; ²Tokyo University of Science, Japan</i>	
A Study on Design of Antenna for PAN Application	221
<i>Kyuwhan Seol, Seohyun Choi, Chonnam National University, Korea</i>	
12GHz Measurement of Transition Duration and Breakdown Field Due to Low Voltage ESD	225
<i>K. Kawamata¹, S. Minegishi², A. Haga², Osamu Fujiwara³; ¹Hachinohe Institute of Technology, Japan ; ²Tohoku Gakuin University, Japan; ³Nagoya Institute of Technology, Japan</i>	
Comparison of Radiated Immunity Tests in Different EMC Test Facilities	229
<i>Holger Streitwolf¹, Ralf Heinrich², Heinz-Günther Behnke¹, Lothar Dallwitz¹, Uwe Karsten²; ¹Physikalisch-Technische Bundesanstalt, Germany ; ²Teseq GmbH, Germany</i>	
Wave Absorber with Circular Lattice Using Metal Mesh for Improving ETC Environment	233
<i>Kouta Matsumoto¹, Yu Miura¹, Takeru Ozawa¹, Osamu Hashimoto¹, Osamu Okada²; ¹Aoyama Gakuin University, Japan ; ²Bridgestone Corporation, Japan</i>	
An Alternative Mathematical Description of HEMP Waveform	237
<i>Yan-zhao Xie, Northwest Institute of Nuclear Technology, China</i>	
A SPICE-Compatible Full-Wave Equivalent Circuit Model for Printed Circuit Structure Analysis ...	241
<i>Eng-Kee Chua¹, Er-Ping Li¹, Kye-Yak See², Wen-Yan Yin³; ¹IIPPC, Singapore ; ²Nanyang Technological University, Singapore; ³Shanghai Jiao Tong University, China</i>	
Influence of Discrete Series Devices on Crosstalk Phenomena in Multiconductor Transmission Lines	245
<i>Ziya Mazloom, Nelson Theethayi, Rajeev Thottappillil, Uppsala University, Sweden</i>	
Measurement and Analysis of Electromagnetic Disturbances in ±500kV Converter Stations	249
<i>Weidong Zhang¹, Xiang Cui¹, Jie Zhao², Xiaolin Li², Qi Wang², Zhibin Zhao¹, Yuanyou Wang²; ¹North China Electric Power University, China ; ²China Southern Power Grid Co. Ltd, China</i>	

Research of Measurements on Electromagnetic Radiation Associated with Power Line Communication (PLC) Networks	253
<i>Yue Xing, Weidong Zhang, Xiang Cui, Xuesong Gu, North China Electric Power University, China</i>	
Ultra-Wideband SSN Suppression in PWR/GND Plane Pairs by Means of a Novel EBG Layer with Triangle Patches	257
<i>Antonio Ciccomancini Scogna, CST of America Inc., USA</i>	
Rigorous Analysis of an Impulse Radiating Antenna with a Non-Ideal Feed Structure	261
<i>James McLean, Robert Sutton, TDK R&D Corp., USA</i>	
SPICE Simulation Method for BCI Component Tests	265
<i>Lutz Weber, Stefan Dickmann, Helmut-Schmidt-Universität, Germany</i>	
Black Box Model and Singular Value Based Model Order Reduction for Interconnects	269
<i>C. Wiegand¹, I.J. Radić-Weissenfeld², C. Hedayat¹, W. John³; ¹University of Paderborn, Germany ; ²Leibniz University of Hannover, Germany; ³Fraunhofer IZM, Germany</i>	
New Approach to EMC Protection	273
<i>T.R. Gazizov, A.M. Zabolotsky, TUSUR, Russia</i>	
Systemic Response After Local Exposition to Low Amplitude HF-EMF in Tomato Plants	277
<i>Catherine Faure¹, David Roux¹, Elisabeth Beauvois¹, Sébastien Girard², Pierre Bonnet², Françoise Paladian², Gérard Ledoit¹, Alain Vian¹; ¹ERTAC, France ; ²LASMEA, France</i>	
Radiation Suppression Ratio Measurement of Noise Suppression Sheet by Compact 3m Method	281
<i>Hirosuke Suzuki, Tomio Hotchi, Masato Inoue, Shigeru Takeda, Keycom Corp., Japan</i>	
Luminosity Characteristics of the Traveling Current Source Return Stroke Models	285
<i>Jovan Cvetić¹, Slavoljub Marković¹, Milica Taušanović²; ¹University of Belgrade, Serbia ; ²Elektrodistribucija Beograd, Serbia</i>	
An Improved Model for Representing Current Waveforms in CMOS Circuits	289
<i>Yan Fu¹, Gian Lorenzo Giuliettini Burbui², Todd Hubing³; ¹Independent Researcher ; ²University of Bologna, Italy; ³Clemson University, USA</i>	
Differential to Common Mode Coupling in Microstrip Lines: Calculation and Improvement	293
<i>Hosein. R. Goodarzi, Majid Tayarani, Saeed Khosravi, Iran University of Science & Technology, Iran</i>	
Optimization of Soybeans as a Biofuel Resource Through Germination Studies Under Electromagnetic Fields	297
<i>David Sleper, M.S. Pathan, Bruno Camps-Raga, Somsak Tantong, Phumin Kirawanich, James E. Thompson, Naz E. Islam, University of Missouri, USA</i>	
Application of Mode Transformers for Characterization of Symmetrical Bi-Modal Planar Transmission Lines	301
<i>Tomasz Stefański¹, Bogdan J. Janiczak²; ¹R&D Marine Technology Centre, Poland ; ²Gdansk University of Technology, Poland</i>	
Transverse Line Parameters of Coupled Microstrips on a Lossy Substrate	305
<i>Dario Assante, Luigi Verolino, University of Naples "Federico II", Italy</i>	
MoM/RCWA Analysis of Frequency Selective Surfaces with Inhomogeneous, Periodic Substrates	309
<i>Arya Fallahi, Christian Hafner, Rüdiger Vahldieck, ETH Zürich, Switzerland</i>	
<hr/>	
Lightning and its Effects 2	
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Influence of Line Routing and Terminations on Transient Overvoltages in LV Power Installations	313
<i>I.A. Metwally¹, F. Heidler²; ¹Sultan Qaboos University, Sultanate of Oman ; ²Universität der Bundeswehr München, Germany</i>	
A Model-Based Parameter Estimation of Current Distribution Along Lightning Return Stroke Channel	317
<i>Hamid R. Karami, Rouzbeh Moini, S.H. Hesam Sadeghi, Amirkabir University of Technology, Iran</i>	
A Non-Linear Antenna Theory Model of Lightning Return Stroke Channel	321
<i>R. Alaee¹, Rouzbeh Moini¹, S. Bonyadi², S.H. Hesam Sadeghi¹; ¹Amirkabir University of Technology, Iran ; ²Razi University, Iran</i>	
Impulse Efficiency of Simple Grounding Electrode Arrangements	325
<i>Leonid Grcev, Ss. Cyril and Methodius University, Macedonia</i>	

Automotive 3

Study of Field Coupling Mechanism at Susceptibility Testing of Automotive Components in the Gigahertz Range	329
<i>Bernd Körber¹, Dieter Sperling¹, Karl-Heinz Gonschorek²; ¹Zwickau University of Applied Sciences, Germany; ²Dresden University of Technology, Germany</i>	
Modeling of Radiated Immunity Measurements by an Active Two-Port Model	333
<i>Stefan Buntz¹, Helmut Leier¹, Stefan Fuchs², Dieter Gwisdalla², Wolfgang Menzel³; ¹DaimlerChrysler AG, Germany; ²Ulm University of Applied Sciences, Germany; ³University of Ulm, Germany</i>	
EMI of Active Front Ends Applied in the Automotive Industry	337
<i>Thomas Fischer¹, Goeran Schubert², Manfred Albach¹; ¹University of Erlangen-Nuremberg, Germany; ²Continental Automotive Systems, Germany</i>	
Enhanced MoM Scheme with Incorporation of General N-Port Networks in Application to Automotive EMC Problems	341
<i>Faik Bogdanov¹, Roman Jobava¹, Stephan Frei², Anna Gheonjian¹, Ekaterina Yavolovskaya¹, Birgit Huneke³, Christian Lippert³; ¹EMCoS, Georgia; ²Universität Dortmund, Germany; ³Audi AG, Germany</i>	

Transients and Power Systems

Fast-Transient Coupling Through a Shielded Cable Penetration	345
<i>Kendall F. Casey¹, William A. Radasky²; ¹SRI International, USA; ²Metatech Corporation, USA</i>	
Reconstruction of Discharge Currents Injected on Calibration Target from Electrostatic Discharge Generators	349
<i>Yoshinori Taka¹, Takashi Adachi¹, Osamu Fujiwara¹, Shinobu Ishigami², Yukio Yamanaka²; ¹Nagoya Institute of Technology, Japan; ²NICT, Japan</i>	
Analytical Formulas of the Electric Field Near a Reinforced Concrete Pole of a MV Line	353
<i>Daniele Desideri, Alvise Maschio, Enrico Poli, University of Padova, Italy</i>	
Simulation Analysis on Radiated EMI from the DC Buses in ±500-kV HVDC Converter Stations ...	357
<i>Zhanqing Yu¹, Jinliang He¹, Bo Zhang¹, Rong Zeng¹, Shuiming Chen¹, Jie Zhao², Qi Wang²; ¹Tsinghua University, China; ²China Southern Power Grid Co. Ltd., China</i>	

Railway EMC

Demonstrating Signalling Compatibility Between Two Train Control Systems	361
<i>Ade Ogunsola¹, Ugo Reggiani², Leonardo Sandrolini²; ¹Parsons Group International, UK; ²University of Bologna, Italy</i>	
On Board Measurements of the Railway's Electromagnetic Noise with Moving Train	365
<i>N. Ben Slimen¹, V. Deniau¹, S. Baranowski², J. Rioult¹, N. Dubalen³, B. Démoulin²; ¹INRETS, France; ²IEMN, France; ³SNCF, France</i>	
DC Components in Pantograph Arcing: Mechanisms and Influence of Various Parameters	369
<i>Dierk Bormann¹, Surajit Midya², Rajeev Thottappillil²; ¹ABB AB, Sweden; ²Uppsala University, Sweden</i>	

Test Methods

A DWT-Based Endpoint Detector for Transient Signals	373
<i>Gunnar Löhning, Harald Schwarz, Brandenburg University of Technology Cottbus, Germany</i>	
Trend Analysis of Insertion Loss Data Associated with Large, Significantly Loaded Compartments	377
<i>Cynthia Ropiak¹, Wilfredo Padilla-Vargas², Frank Peterkin²; ¹SAQ Consulting Ltd., USA; ²Naval Surface Warfare Center Dahlgren Division, USA</i>	
A Low-Noise Realtime Time-Domain EMI Measurement System	381
<i>Stephan Braun, Arnd Frech, Peter Russer, Technische Universität München, Germany</i>	
Uncertainty Contributions to the Clamp Factor CF of the Absorbing Clamp	385
<i>Heinrich Ryser, METAS, Switzerland</i>	

System EMC 1

Aspects of Random-Lay Multiconductor Cable Propagation Which Are Not Statistical	389
<i>Carl E. Baum, University of New Mexico, USA</i>	
ATV System Radiated Susceptibility Test	393
<i>André Schaffar¹, Manuel Ramos¹, Vincent Pery¹, Loïc Bruneau¹, Philippe Laget², Jacob Van der Meulen²; ¹ASTRIUM Space Transportation, France ; ²ESA ESTEC, The Netherlands</i>	
Assessment of High Frequency Coupling in a Generic Object by the Power Balance Method	397
<i>Isabelle Junqua, Laurent Guibert, Jean-Philippe Parmantier, ONERA, France</i>	
Numerical Evaluation of EMI Immunity of Hard Disk Drive with Multiple Slots	401
<i>Xianke Gao, Seagate Technology International, Singapore</i>	

Radiated Emissions

Comparison of Electric Field Strength at VHF Frequencies Generated by Dipoles and TEM Cells	405
<i>Tian Hong Loh, Benjamin Loader, Martin Alexander, National Physical Laboratory, UK</i>	
Time-Domain Processing to Determine Free-Space Antenna Factor	409
<i>Dennis Camell, Robert T. Johnk, NIST, USA</i>	
On the Interaction Between the DUT's Radar Cross Section and the Reactive Effect of TEM Cells	413
<i>David Pouhè, Gerhard Mönich, Technische Universität Berlin, Germany</i>	
Method for Measuring Radiated Electric Field Excited by Linear Array Antenna Using Near Field to Far Field Transformation	417
<i>Junji Higashiyama, Yoshiaki Tarusawa, NTT DoCoMo Inc., Japan</i>	

Magnetic Resonance

EM Modeling and MR: Overview and Safety Topics	421
<i>Christopher M. Collins, Pennsylvania State University, USA</i>	
Interventional MR: Devices, Applications, Electromagnetic Safety Concerns	425
<i>Harald H. Quick, University Hospital Essen, Germany</i>	

System EMC 2

Double Bulk Current Injection Test with Amplitude and Phase Control	429
<i>Filippo Marliani¹, Giordano Spadacini², Sergio A. Pignari²; ¹ESA ESTEC, The Netherlands ; ²Politecnico di Milano, Italy</i>	
Time Variation of the Powerline Channel Simultaneously with Impulsive Noise	433
<i>G. Avril¹, F. Gauthier¹, F. Moulin¹, Ahmed Zeddam¹, F. Nouvel²; ¹France Télécom, France ; ²IETR, France</i>	
Investigation on Mechanism of Radiated Emissions from Fan Unit Model	437
<i>Ran Wang¹, Nobuo Kuwabara¹, Kiyoshi Masui², Hideya Sato²; ¹Kyushu Institute of Technology, Japan ; ²Daiwa Institute of Research Ltd., Japan</i>	
On Improving xDSL Performances by Applying Particular Methods of Crosstalk Reduction	441
<i>Sandrine Roblot¹, Ahmed Zeddam¹, Alain Reineix²; ¹France Télécom, France ; ²XLIM, France</i>	
Electromagnetic Environmental Analysis at the Sewage Treatment Center	445
<i>Eugene Rhee, Joong-Geun Rhee, Hanyang University, Korea</i>	

EMC Standards, Regulation, and Spectrum Management

Updates on the New Release of IEC 61000-4-3 Edition 3	449
<i>Jason H. Smith, AR RF/Microwave Instrumentation, USA</i>	
EMC in Romania When Joining EU	453
<i>Andrei Marinescu¹, Radu Enescu², Lucian Ursea³; ¹ACER, Romania ; ²ANRCTI, Romania; ³MEF, Romania</i>	
Conditions of Electromagnetic Compatibility of Radio Links: A Method of Calculation	457
<i>N. Azamatov¹, Yu. Mosienko², V. Voloshin², V. Veretynsky², S. Kuntsevich²; ¹State Defence Industry Committee, Belarus ; ²Agat State Research & Production Association, Belarus</i>	

Reverberation Chambers	
Effect of the Size of the Antenna on Measurements Distribution in Reverberation Chamber	461
<i>Christophe Lemoine, Philippe Besnier, M'hamed Drissi, IETR, France</i>	
Electrical Mode Stirring by Reactively Loaded Antennas in Reverberating Chambers for EMC ...	465
<i>Edgar Voges, Tobias Eisenburger, Dirk Peier, University of Dortmund, Germany</i>	
Using Autoregressive Models to Estimate the Number of Independent Samples Available with Stirrer Rotation in Reverberation Chamber	469
<i>Christophe Lemoine, Philippe Besnier, M'hamed Drissi, IETR, France</i>	
Figures of Merit for a Hybrid TEM-Reverberation Chamber	473
<i>Paul Kay¹, Franz Schlagenhauser², Hongmei Fan²; ¹University of South Australia, Australia ; ²WATRI, Australia</i>	
Conducted Test Methods	
An Indirect Alternative Method of Measurement for Conducted Emissions of High-Power Equipments	477
<i>Stephane Coets, Veronique Beauvois, University of Liege, Belgium</i>	
Method of Measuring Voltage Without Cable Correction by Loading Capacitance Changeable CVP	481
<i>Hideaki Takahashi¹, Nobuo Kuwabara¹, Fujio Amemiya², Mitsuo Hattori²; ¹Kyushu Institute of Technology, Japan ; ²NTT Advanced Technology Corporation, Japan</i>	
Impact of the Symmetry of Coupling-Decoupling Networks on the Conducted Immunity Testing of PLC Modems	485
<i>Marcos Rubinstein¹, Ana Vukicevic², Farhad Rachidi², José-Luis Bermudez³; ¹University of Applied Sciences of Western Switzerland, Switzerland ; ²EPFL, Switzerland; ³ABB Sécheron, Switzerland</i>	
Improved Adapters for the Accurate Calibration of LISN Input Impedance	489
<i>Michele Borsero¹, Claudio Pravato², Alessandro Sona³, Marco Stellini³, Alessandro Zuccato²; ¹INRIM, Italy ; ²CREI Ven, Italy; ³University of Padova, Italy</i>	
Measurement Errors Caused by the Transient Limiter	493
<i>Tim Williams, Elmac Services, UK</i>	
EMC Protection	
Field Compensation for Resistance Welding	497
<i>Ronny Herms, Guido Bartels, Reinhard Doebbelin, Andreas Lindemann, Otto von Guericke University of Magdeburg, Germany</i>	
A New Behavioural Model for Performance Evaluation of Common Mode Chokes	501
<i>Anne Roc'h¹, Hans Bergsma², Dongsheng Zhao³, Braham Ferreira³, Frank Leferink¹; ¹University of Twente, The Netherlands ; ²Thales Netherlands, The Netherlands; ³Delft University of Technology, The Netherlands</i>	
SMPS Tools for EMI Filter Optimization	505
<i>Yannick Poiré¹, Olivier Maurice¹, Mohamed Ramdani², M'hamed Drissi³, Alain Sauvage⁴; ¹EADS, France ; ²ESEO, France; ³IETR, France; ⁴Airbus, France</i>	
